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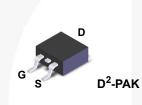
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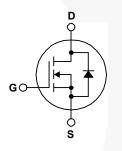
N-Channel PowerTrench[®] MOSFET 75 V, 80 A, 4.5 m Ω

Features

- $R_{DS(on)}$ = 3.9 m Ω (Typ.) @ V_{GS} = 10 V, I_D = 80 A
- Q_{G(tot)} = 92 nC (Typ.) @ V_{GS} = 10 V
- Low Miller Charge
- Low Q_{rr} Body Diode
- UIS Capability (Single Pulse and Repetitive Pulse)

Formerly developmental type 82684





Synchronous Rectification for ATX / Server / Telecom PSU

Motor drives and Uninterruptible Power Supplies

MOSFET Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter	FDB045AN08A0	Units	
V _{DSS}	Drain to Source Voltage	75	V	
V _{GS}	Gate to Source Voltage	±20	V	
ID	Drain Current			
	Continuous ($T_C < 137^{\circ}C$, $V_{GS} = 10V$)	90	А	
	Continuous ($T_{amb} = 25^{\circ}C$, $V_{GS} = 10V$, with $R_{\theta JA} = 43^{\circ}C/W$)	19	Α	
	Pulsed	Figure 4	А	
E _{AS}	Single Pulse Avalanche Energy (Note 1)	600	mJ	
P _D	Power dissipation	310	W	
	Derate above 25°C	2.0	W/ºC	
T _J , T _{STG}	Operating and Storage Temperature	-55 to 175	°C	

Applications

Battery Protection Circuit

Thermal Characteristics

$R_{ ext{ heta}JC}$	Thermal Resistance Junction to Case	0.48	°C/W
R_{\thetaJA}	Thermal Resistance Junction to Ambient (Note 2)	62	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient, 1in ² copper pad area	43	°C/W

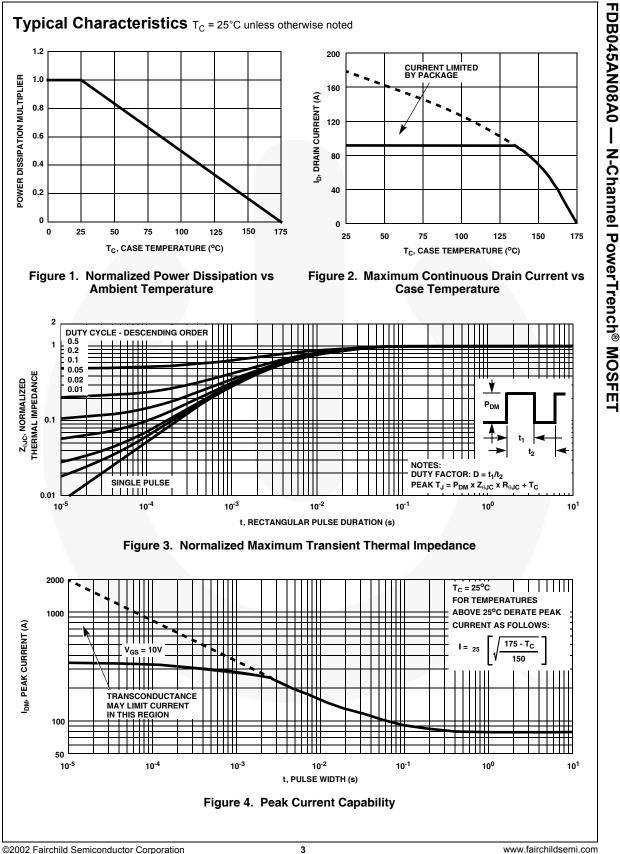
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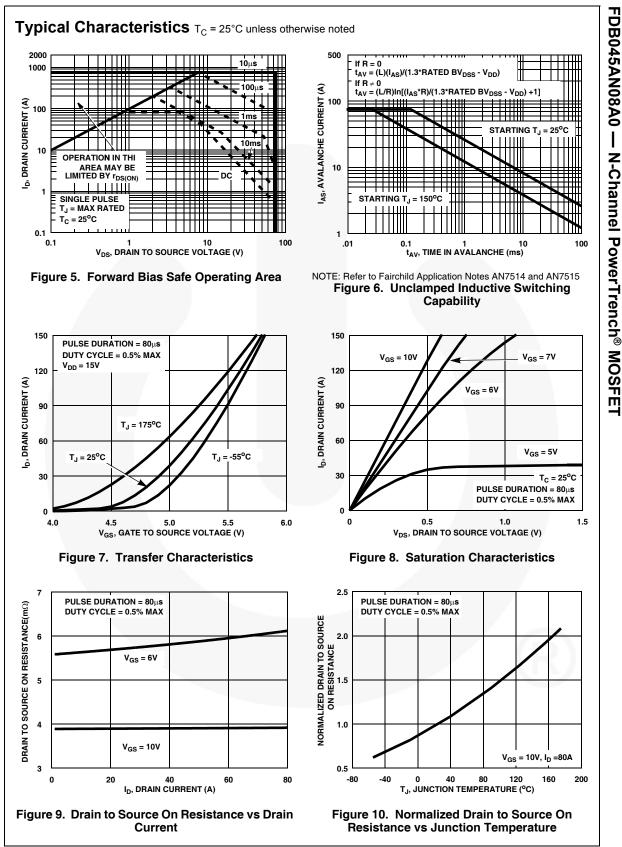
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FDB045A Electrica Symbol Off Charao		FDB045AN08A0							
Symbol	al Chara		D ² -PAK 330 mm		Tape Width 24 mm		Quantity 800 units		
Symbol		acteristics T _c = 25°C	unless otherwise	e noted					
Off Charad		Parameter		Conditions	Min	Тур	Max	Units	
	cteristics	6							
B _{VDSS}	Drain to S	ource Breakdown Voltage	I _D = 250μA, \	/ _{GS} = 0V	75	-	-	V	
	5		$V_{DS} = 60V$		-	-	1	۸	
I _{DSS} Zero G		Gate Voltage Drain Current	$V_{GS} = 0V$	$T_{C} = 150^{\circ}C$		-	250	μΑ	
I _{GSS}	Gate to Source Leakage Current		$V_{GS} = \pm 20V$		-	-	±100	nA	
On Charac	cteristics	5							
V _{GS(TH)}	Gate to So	ource Threshold Voltage	$V_{GS} = V_{DS}, I_{I}$	o = 250μA	2	-	4	V	
/			I _D = 80A, V _{G8}		-	0.0039	0.0045		
(DO/ON)	Drain to S	ource On Resistance	$I_{\rm D} = 37 {\rm A}, {\rm V}_{\rm GS}$	_S = 6V	-	0.0056	0.0084	Ω	
ÍDS(ON)	Diamito S	Suce on nesistance	I _D = 80A, V _G T _J = 175°C	₃ = 10V,	-	0.008	0.011		
Dynamic (Characte	ristics							
C _{ISS}	Input Capa				_	6600	-	pF	
C _{OSS}	Output Ca		V _{DS} = 25V, V	_{GS} = 0V,	-	1000	-	pF	
C _{RSS}	•	ransfer Capacitance	f = 1MHz		-	240	-	pF	
Q _{g(TOT)}		Charge at 10V	V _{GS} = 0V to 1	ov		92	138	nC	
∝ _{g(101)} Q _{g(TH)}		Gate Charge		$V_{DD} = 40V$	_	11	17	nC	
∝ _{g(1H)} Q _{gs}		ource Gate Charge	GS - CT IO I	I _D = 80A	-	27	-	nC	
Q _{gs2}		ge Threshold to Plateau		$I_{g} = 1.0 \text{mA}$	-	16	-	nC	
Q _{gs2} Q _{gd}		ain "Miller" Charge		9	-	21	-	nC	
	Charact	eristics (V _{GS} = 10V)					1 1		
t _{on}	Turn-On T					-	160	ns	
	Turn-On D					18	-	ns	
t _r	Rise Time			$V_{DD} = 40V, I_D = 80A$ $V_{GS} = 10V, R_{GS} = 3.3\Omega$		88	-	ns	
t _{d(OFF)}	Turn-Off D	elav Time				40	-	ns	
t _f	Fall Time					45	-	ns	
OFF	Turn-Off T	ime			-	-	128	ns	
	rce Diod	e Characteristics				1			
			I _{SD} = 80A		-	-	1.25	V	
V _{SD}		Drain Diode Voltage	$I_{SD} = 40A$	I _{SD} = 40A		-	1.0	V	
t _{rr}		ecovery Time	$I_{SD} = 75A$, $dI_{SD}/dt = 100A/\mu s$		-	-	53	ns	
Q _{RR}	Reverse H	ecovered Charge	I_{SD} = 75A, d I_{SD} /dt = 100A/µs		-	-	54	nC	

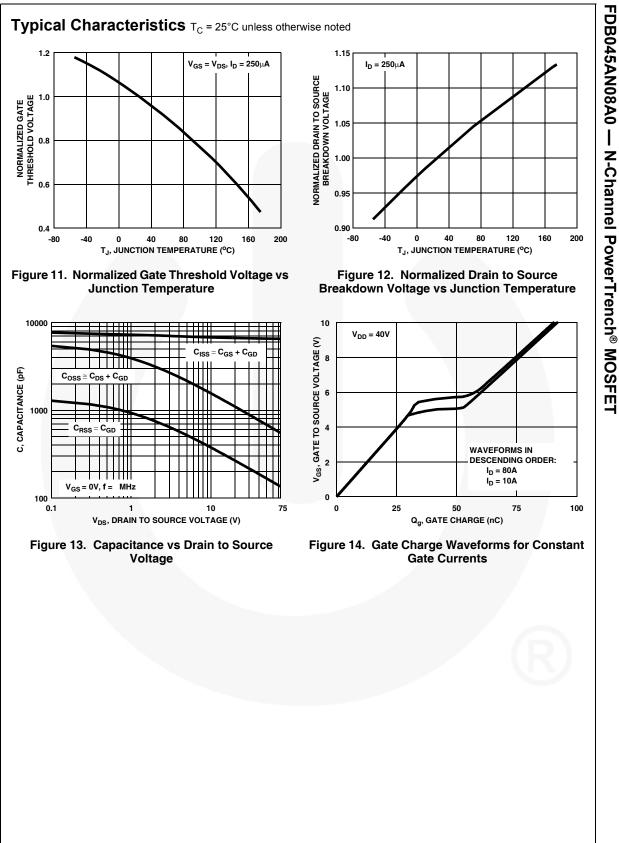
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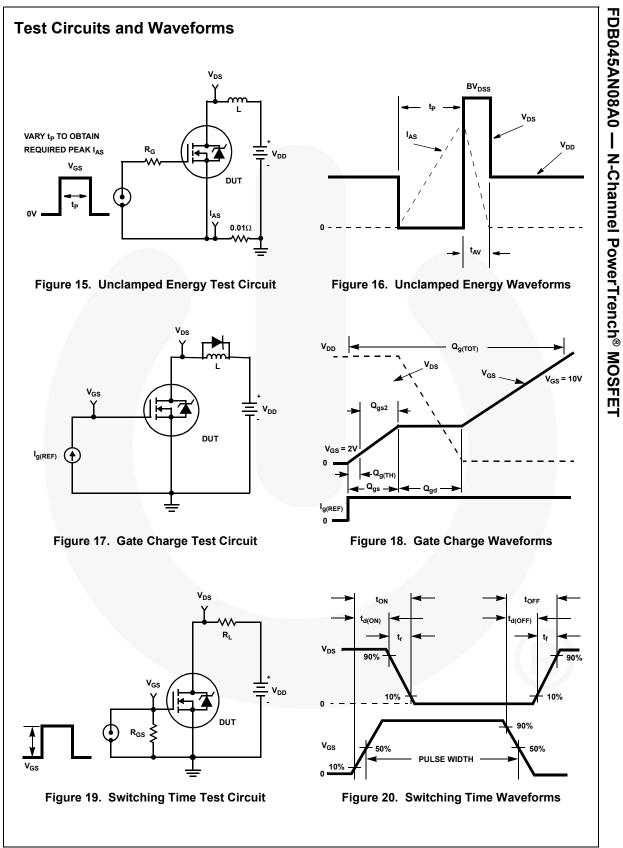


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Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, T_A (°C), and thermal resistance $R_{\theta JA}$ (°C/W) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}}$$
(EQ. 1)

In using surface mount devices such as the TO-263 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

- Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- 2. The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- 6. For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the $R_{\theta JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

$$R_{\theta JA} = 26.51 + \frac{19.84}{(0.262 + Area)}$$
(EQ. 2)

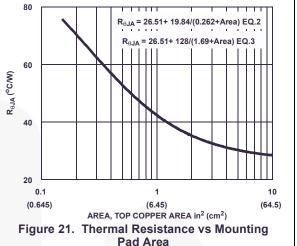
Area in Inches Squared

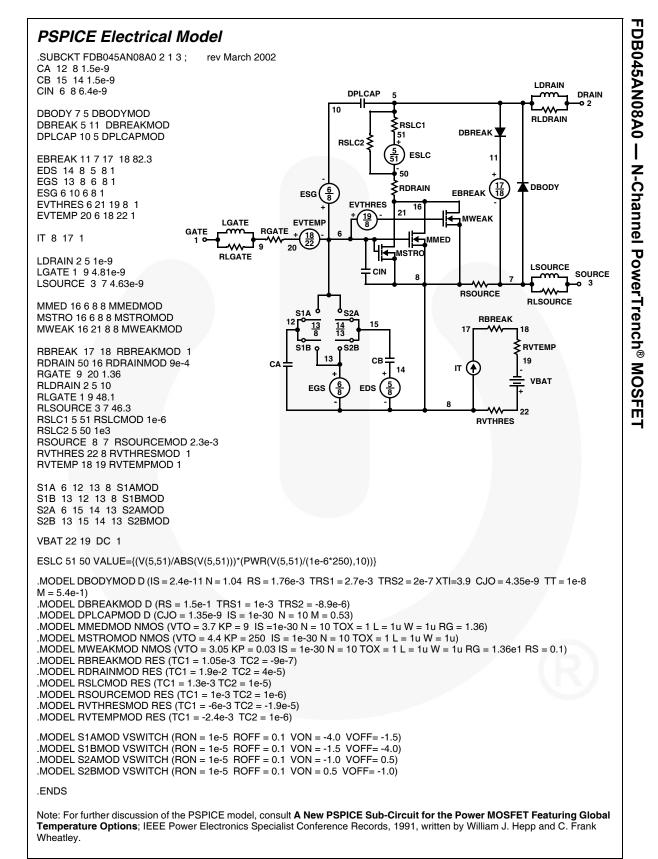
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$$R_{\theta JA} = 26.51 + \frac{128}{(1.69 + Area)}$$
 (EQ. 3)

Area in Centimeters Squared

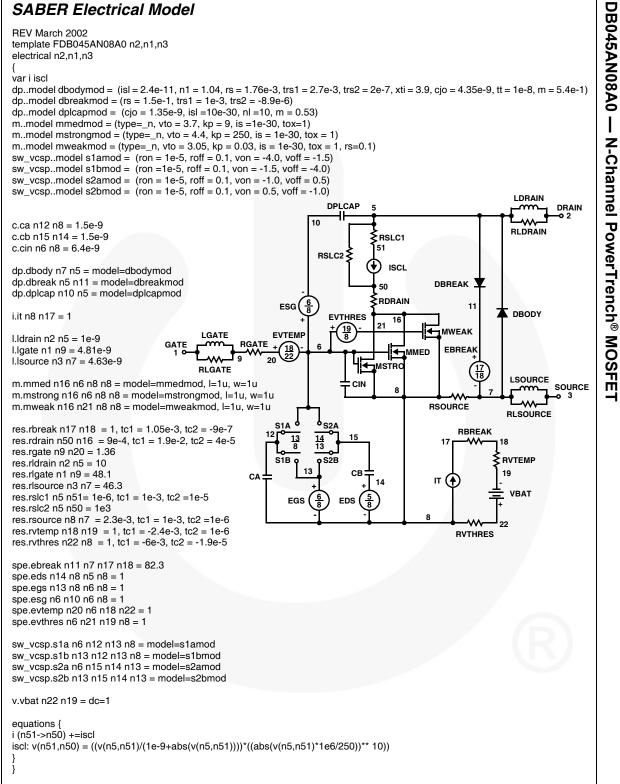
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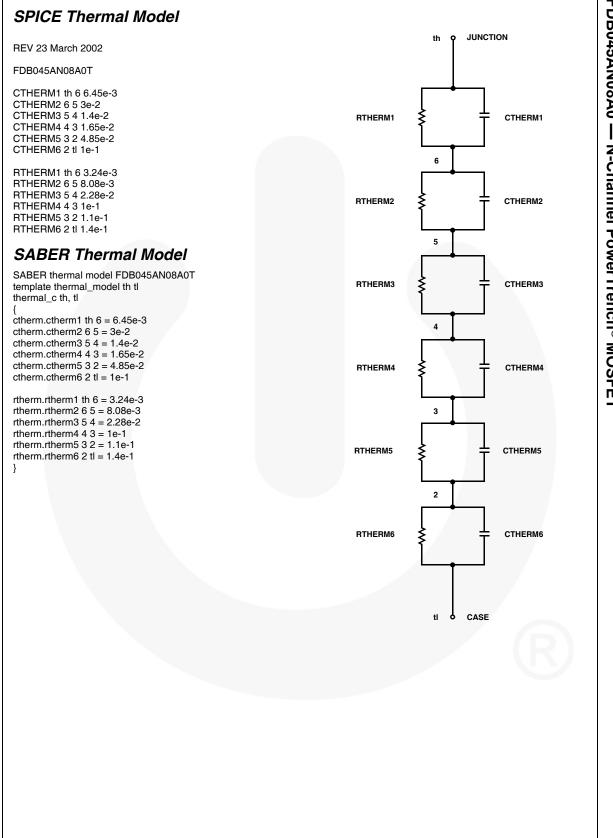


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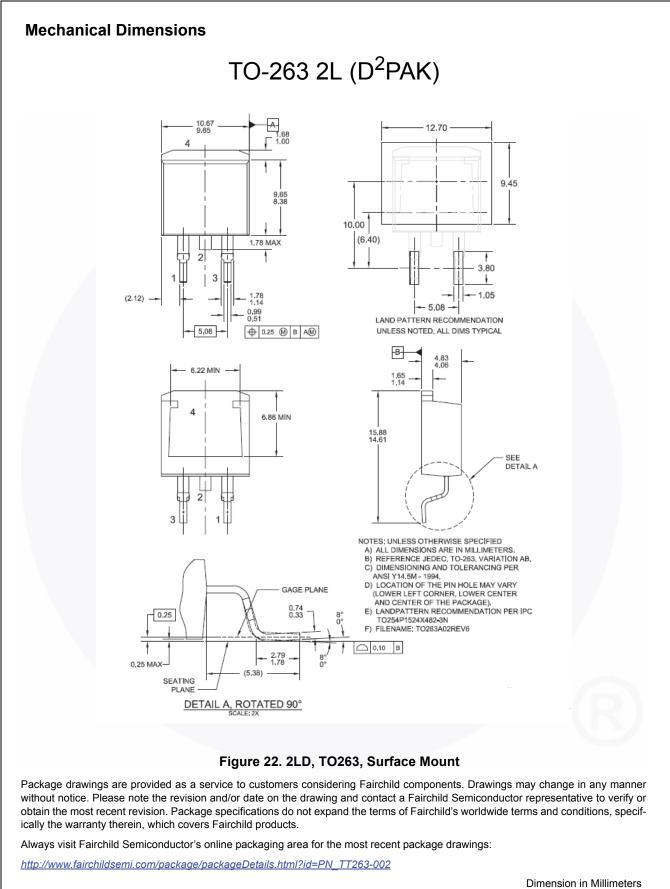
SABER Electrical Model



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Not In Production

Obsolete

Datasheet contains specifications on a product that is discontinued by Fairchild

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